

Application/Control No.	Applicant(s)/Patent under Reexamination
09/847,606	PECK ET AL.
Examiner	Art Unit
Quoc A Tran	2176

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Class	Subclass	Date	Examiner
715	517	10/14/2005	QX
update	seach	3/23/2006	W
UpDated	Above	06/12/2006	03

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
715	513	6/12/2006	
715	522	6/12/2006	
715	830	6/12/2006	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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Search Notes	Application No.	Applicant(s)	
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	SEAR	CHED	
Class	Subclass	Date	Examiner
715	5/2 500.1 501.1 522	5/21/24	
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